





TPS74801-Q1

# SLVSAI4E - SEPTEMBER 2010 - REVISED SEPTEMBER 2024

# TPS74801-Q1 Automotive, 1.5A, Low-Dropout Linear Regulator With Programmable Soft-Start

#### 1 Features

- AEC-Q100 qualified for automotive applications: Temperature grade 1: –40°C to +125°C, T<sub>A</sub>
- V<sub>OUT</sub> range: 0.8V to 3.6V
- Ultra-low V<sub>IN</sub> range: 0.8V to 5.5V
- V<sub>BIAS</sub> range 2.7V to 5.5V
- Low dropout: 60mV typ at 1.5A,  $V_{BIAS} = 5V$
- Power-good (PG) output allows supply monitoring or provides a sequencing signal for other supplies
- 2% accuracy over line, load, and temperature
- Programmable soft-start provides linear voltage
- V<sub>BIAS</sub> permits low V<sub>IN</sub> operation with good transient response
- Stable with any output capacitor ≥ 2.2µF
- Available in small 3mm × 3mm × 1mm VSON-10 and 5mm × 5mm VQFN-20 packages

### 2 Applications

- Telematic control units
- Infotainment and clusters
- Automotive head units
- Medium-, short-range radar

## 3 Description

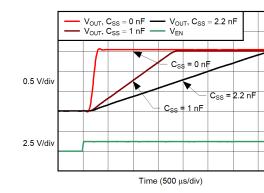
The TPS74801-Q1 low-dropout (LDO) linear regulator provides an easy-to-use robust power management solution for a wide variety of applications. Userprogrammable soft-start minimizes stress on the input power source by reducing capacitive inrush current on start-up. The soft-start is monotonic and designed for powering many different types of processors and ASICs. The enable input and power-good output allow easy sequencing with external regulators. This complete flexibility allows a solution to be configured that meets the sequencing requirements of FPGAs, DSPs, and other applications with special start-up requirements.

A precision reference and error amplifier delivers 2% accuracy over load, line, temperature, and process. The device is stable with any type of output capacitor greater than or equal to 2.2µF, and is fully specified for  $T_J = -40^{\circ}$ C to +150°C for the new chip,  $T_J = -40^{\circ}$ C to +105°C for the DRC package, and  $T_{J} = -40$ °C to +125°C for the RGW package. The TPS74801-Q1 is offered in a small 3mm × 3mm VSON-10 package, yielding a highly compact, total solution size. The device is also available in a 5mm × 5mm VQFN-20.

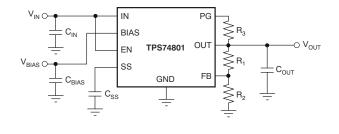
**Package Information** 

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE <sup>(2)</sup>
TPS74801-Q1	DRC (VSON, 10)	3mm × 3mm
1PS/4801-Q1	RGW (VQFN, 20)	5mm × 5mm

- For more information, see the Mechanical, Packaging, and Orderable Information
- The package size (length × width) is a nominal value and includes pins, where applicable.



**Turn-On Response** 



Typical Application Circuit (Adjustable)



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# **4 Pin Configuration and Functions**

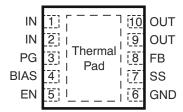


Figure 4-1. DRC Package, 10-Pin VSON With Exposed Thermal Pad (Top View)

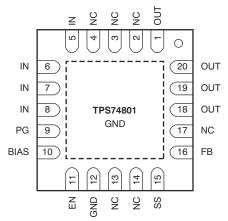


Figure 4-2. RGW Package, 20-Pin VQFN With Exposed Thermal Pad (Top View)

**Table 4-1. Pin Functions** 

	PIN			
	NO.		TYPE	DESCRIPTION
NAME	DRC (VSON)	RGW (VQFN)	=	
BIAS	4	10	I	Bias input voltage for error amplifier, reference, and internal control circuits.
EN	5	11	I	Enable pin. Driving this pin high enables the regulator. Driving this pin low puts the regulator into shutdown mode. This pin must not be left unconnected.
FB	8	16	I	Feedback pin. The feedback connection to the center tap of an external resistor divider network that sets the output voltage. This pin must not be left floating.
GND	6	12	_	Ground
IN	1, 2	5-8	I	Input to the device.
NC	N/A	2-4, 13, 14, 17	_	No connection. This pin can be left floating or connected to GND to allow better thermal contact to the top-side plane.
OUT	9, 10	1, 18-20	0	Regulated output voltage. A small capacitor (total typical capacitance ≥ 2.2 µF, ceramic) is needed from this pin to ground to provide stability.
PG	3	9	0	Power-good pin. An open-drain, active-high output that indicates the status of V <sub>OUT</sub> . When V <sub>OUT</sub> exceeds the PG trip threshold, the PG pin goes into a high-impedance state. When V <sub>OUT</sub> is below this threshold the pin is driven to a low-impedance state. Connect a pullup resistor from 10 k $\Omega$ to 1 M $\Omega$ from this pin to a supply of up to 5.5 V. The supply can be higher than the input voltage. Alternatively, the PG pin can be left unconnected if output monitoring is not necessary.
ss	7	15	_	Soft-start pin. A capacitor connected on this pin to ground sets the start-up time. If this pin is left unconnected, the regulator output soft-start ramp time is typically 200 µs.
Thermal Pa	d		_	Solder the thermal pad to the ground plane for increased thermal performance.

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# **5 Specifications**

# 5.1 Absolute Maximum Ratings

over operating temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V <sub>IN</sub> , V <sub>BIAS</sub>	Input voltage	-0.3	6	V
V <sub>EN</sub>	Enable voltage	-0.3	6	V
$V_{PG}$	Power-good voltage	-0.3	6	V
I <sub>PG</sub>	PG sink current	0	1.5	mA
V <sub>SS</sub>	Soft-start voltage	-0.3	6	V
V <sub>FB</sub>	Feedback voltage	-0.3	6	V
V <sub>OUT</sub>	Output voltage	-0.3	V <sub>IN</sub> + 0.3	V
I <sub>OUT</sub>	Output current	Internally I	imited	
I <sub>CL</sub>	Output short-circuit duration	Indefin	ite	
P <sub>DISS</sub>	Continuous total power dissipation	See Thermal Information		
TJ	Junction temperature	-40	150	°C
T <sub>stg</sub>	Storage temperature	-55	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000	V
V <sub>(ESD)</sub>	Liectiostatic discharge	Charged device model (CDM), per AEC specification Q100-011	±500	·

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

### 5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V <sub>IN</sub>	Input supply voltage	V <sub>OUT</sub> + V <sub>DO</sub> (V <sub>IN</sub> )	V <sub>OUT</sub> + 0.3	5.5	V
V <sub>EN</sub>	Enable supply voltage		V <sub>IN</sub>	5.5	V
V <sub>BIAS</sub> (1)	Bias supply voltage	$V_{OUT} + V_{DO} (V_{BIAS})^{(2)}$	V <sub>OUT</sub> + 1.6 <sup>(2)</sup>	5.5	V
V <sub>OUT</sub>	Output voltage	0.8		3.6	V
I <sub>OUT</sub>	Output current	0		1.5	Α
C <sub>OUT</sub>	Output capacitor	2.2			μF
C <sub>IN</sub>	Input capacitor <sup>(3)</sup>	1			μF
C <sub>BIAS</sub>	Bias capacitor	0.1	1		μF
TJ	Operating junction temperature	-40		150	°C

- (1) BIAS supply is required when  $V_{\text{IN}}$  is below  $V_{\text{OUT}}$  + 1.62 V.
- (2)  $V_{BIAS}$  has a minimum voltage of 2.7 V or  $V_{OUT} + V_{DO}$  ( $V_{BIAS}$ ), whichever is higher.
- (3) If  $V_{IN}$  and  $V_{BIAS}$  are connected to the same supply, the recommended minimum capacitor for the supply is 4.7  $\mu$ F.

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### **5.4 Thermal Information**

	THERMAL METRIC(1)		TPS74801-Q1				
			RGW (VQFN) (new chip)	DRC (VSON) (legacy chip)	DRC (VSON) (new chip)	UNIT	
		20 PINS	20 PINS	10 PINS	10 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	35.6	34.7	44.2	47.2	°C/W	
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	33.3	31	50.3	63.7	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	15	13.5	19.6	19.5	°C/W	
ΨЈТ	Junction-to-top characterization parameter	0.4	1.4	0.7	4.2	°C/W	
ΨЈВ	Junction-to-board characterization parameter	15.2	13.5	17.8	19.4	°C/W	
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	3.8	3.6	4.3	3.3	°C/W	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.



## **5.5 Electrical Characteristics**

at  $V_{EN}$  = 1.1 V,  $V_{IN}$  =  $V_{OUT}$  + 0.3 V,  $C_{BIAS}$  = 0.1  $\mu$ F,  $C_{IN}$  =  $C_{OUT}$  = 10  $\mu$ F,  $C_{NR}$  = 1 nF,  $I_{OUT}$  = 50 mA,  $V_{BIAS}$  = 5.0 V,  $T_A$  =  $-40^{\circ}$ C to 105°C (DRC),  $T_A$  =  $-40^{\circ}$ C to 125°C (RGW) and  $T_J$  = -40 to 150°C (New Chip) (unless otherwise noted); typical values are at  $T_{IJ}$  = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
V <sub>REF</sub>	Internal reference (Adj.)	T <sub>A</sub> = 25°C	0.796	0.8	0.804	V	
	Output voltage range	V <sub>IN</sub> = 5 V, I <sub>OUT</sub> = 1.5 A	V <sub>REF</sub>		3.6	V	
V <sub>OUT</sub>	40	$2.97 \text{ V} \le \text{V}_{\text{BIAS}} \le 5.5 \text{ V}, 50 \text{ mA} \le \text{I}_{\text{OUT}} \le 1.5 \text{ A} \text{ (legacy chip)}$	-2 ±0.5 2		2	0/	
	Accuracy <sup>(1)</sup>	$2.97 \text{ V} \le \text{V}_{\text{BIAS}} \le 5.5 \text{ V}, 50 \text{ mA} \le \text{I}_{\text{OUT}} \le 1.5 \text{ A (new chip)}$	-1.35	±0.3	1.35	5 %	
۸۱/	Line regulation	$V_{OUT(nom)} + 0.3 \le V_{IN} \le 5.5 \text{ V (legacy chip)}$		0.03		%/V	
$\Delta V_{OUT (\Delta VIN)}$	Line regulation	$V_{OUT(nom)} + 0.3 \le V_{IN} \le 5.5 \text{ V (new chip)}$		0.001		70/ V	
$\Delta V_{OUT (\Delta IOUT)}$	Load regulation	50 mA ≤ I <sub>OUT</sub> ≤ 1.5 A		0.09		%/A	
		$I_{OUT}$ = 1.5 A, $V_{BIAS} - V_{OUT(nom)} \ge 3.25 \text{ V (legacy chip)}$ (3)		60	165		
	V <sub>IN</sub> dropout voltage <sup>(2)</sup>	$I_{OUT}$ = 1.5 A, $V_{BIAS} - V_{OUT(nom)} \ge 3.25 \text{ V (DRC: new chip)}$ (3)		50	100	mV	
$V_{DO}$		$I_{OUT}$ = 1.5 A, $V_{BIAS} - V_{OUT(nom)} \ge 3.25 \text{ V (RGW: new chip)}$ (3)		50	110		
	V <sub>BIAS</sub> dropout voltage <sup>(2)</sup>	I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = V <sub>BIAS</sub> (legacy chip)		1.31	1.6	V	
	VBIAS diopout voltage	I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = V <sub>BIAS</sub> (new chip)		1.31	1.43	V	
I <sub>CL</sub>	Output current limit	V <sub>OUT</sub> = 80% × V <sub>OUT(nom)</sub>	2		5.5	Α	
ı	DIA Coming account	(Legacy chip)		1	2	mA	
I <sub>BIAS</sub>	BIAS pin current	(New chip)		1	1.2		
I <sub>SHDN</sub>	Shutdown supply current	V <sub>EN</sub> ≤ 0.4 V (legacy chip)		1	50		
I <sub>SHDN (smart</sub>	Shutdown supply current (I <sub>GND</sub> )	V <sub>EN</sub> ≤ 0.4 V (new chip)		0.85	10	μΑ	
I	Foodbook nin ourrent	(Legacy chip)	-1	0.15	1	μA	
I <sub>FB</sub>	Feedback pin current	(New chip)	-30	0.15	30	nA	
		1 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (legacy chip)		60		dB	
	Power-supply rejection	1 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (new chip)		69			
	(V <sub>IN</sub> to V <sub>OUT</sub> )	300 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (legacy chip)		30			
DODD		300 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (new chip)		49			
PSRR		1 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (legacy chip)		50		dB	
	Power-supply rejection	1 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (new chip)		59			
	(V <sub>BIAS</sub> to V <sub>OUT</sub> )	300 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (legacy chip)		30			
		300 kHz, I <sub>OUT</sub> = 1.5 A, V <sub>IN</sub> = 1.8 V, V <sub>OUT</sub> = 1.5 V (new chip)		50			
W	Output poice valtage	BW = 100 Hz to 100 kHz, I <sub>OUT</sub> = 1.5 A, C <sub>SS</sub> = 1 nF (legacy chip)		25 × V <sub>OUT</sub>		11\/200 -	
V <sub>n</sub>	Output noise voltage	BW = 100 Hz to 100 kHz, I <sub>OUT</sub> = 1.5 A, C <sub>SS</sub> = 1 nF (new chip)		20 × V <sub>OUT</sub>		μVrms	
	National contract of the second	R <sub>LOAD</sub> for I <sub>OUT</sub> = 1.0 A, C <sub>SS</sub> = open (legacy chip)		200			
t <sub>STR</sub>	Minimum startup time	R <sub>LOAD</sub> for I <sub>OUT</sub> = 1.0 A, C <sub>SS</sub> = open (new chip)		250		μs	

# **5.5 Electrical Characteristics (continued)**

at  $V_{EN}$  = 1.1 V,  $V_{IN}$  =  $V_{OUT}$  + 0.3 V,  $C_{BIAS}$  = 0.1  $\mu$ F,  $C_{IN}$  =  $C_{OUT}$  = 10  $\mu$ F,  $C_{NR}$  = 1 nF,  $I_{OUT}$  = 50 mA,  $V_{BIAS}$  = 5.0 V,  $T_A$  =  $-40^{\circ}$ C to 105°C (DRC),  $T_A$  =  $-40^{\circ}$ C to 125°C (RGW) and  $T_J$  = -40 to 150°C (New Chip) (unless otherwise noted); typical values are at  $T_{JJ}$  = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
	Soft-start charging	V <sub>SS</sub> = 0.4 V (legacy chip)		440		nA	
I <sub>SS</sub>	current	V <sub>SS</sub> = 0.4 V (new chip)		530		ΠA	
V <sub>EN(hi)</sub>	Enable input high level		1.1		5.5	V	
V <sub>EN(lo)</sub>	Enable input low level		0		0.4	V	
	Enable nin hyateresia	(Legacy chip)		50		m)/	
V <sub>EN(hys)</sub>	Enable pin hysteresis	(New chip)		55	mV		
V <sub>EN(dg)</sub>	Enable pin deglitch time			20		μs	
1	Frankla nin avenuet	V <sub>EN</sub> = 5 V (legacy chip)		0.1	1		
I <sub>EN</sub> Enable pin current	V <sub>EN</sub> = 5 V (new chip)		0.1	0.3	μA		
V <sub>IT</sub>	PG trip threshold	V <sub>OUT</sub> decreasing	85	90	94	%V <sub>OUT</sub>	
V <sub>HYS</sub>	PG trip hysteresis			3		%V <sub>OUT</sub>	
\/	DC output low voltage	I <sub>PG</sub> = 1 mA (sinking), V <sub>OUT</sub> < V <sub>IT</sub> (legacy chip)			0.3		
$V_{PG(lo)}$	PG output low voltage	I <sub>PG</sub> = 1 mA (sinking), V <sub>OUT</sub> < V <sub>IT</sub> (new chip)			0.125	V	
	DC la alca na accumant	V <sub>PG</sub> = 5.25 V, V <sub>OUT</sub> > V <sub>IT</sub> (legacy chip)		0.1	1		
I <sub>PG(lkg)</sub> PG leakage current		V <sub>PG</sub> = 5.25 V, V <sub>OUT</sub> > V <sub>IT</sub> (new chip)		0.001	0.05	μA	
<b>-</b>	Thermal shutdown	Shutdown, temperature increasing		165		°C	
$T_{SD}$	temperature	Reset, temperature decreasing		140		°C	
R <sub>PULLDOWN</sub>		V <sub>BIAS</sub> = 5V, V <sub>EN</sub> = 0 V		0.83		kΩ	

<sup>(1)</sup> Adjustable devices tested at 0.8 V; resistor tolerance is not taken into account.

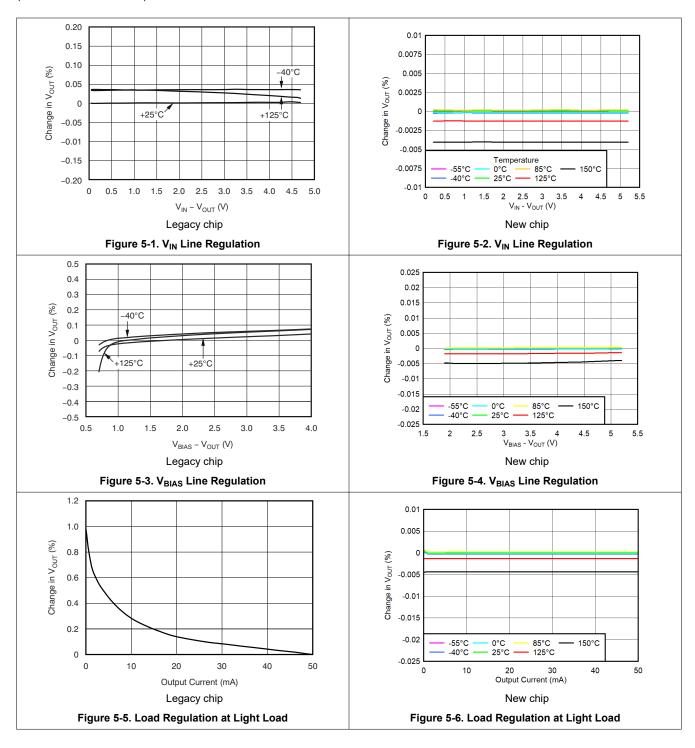
<sup>(2)</sup> Dropout is defined as the voltage from  $V_{IN}$  to  $V_{OUT}$  when  $V_{OUT}$  is 3% below nominal.

<sup>(3) 3.25</sup> V is a test condition of this device and can be adjusted by referring to Figure 6-6.



## 5.6 Typical Characteristics: I<sub>OUT</sub> = 50 mA

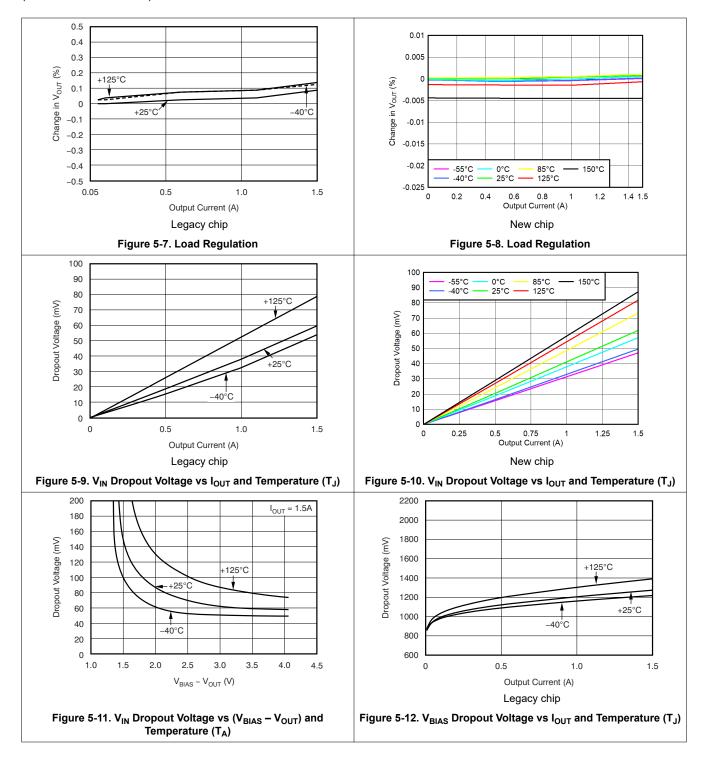
at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



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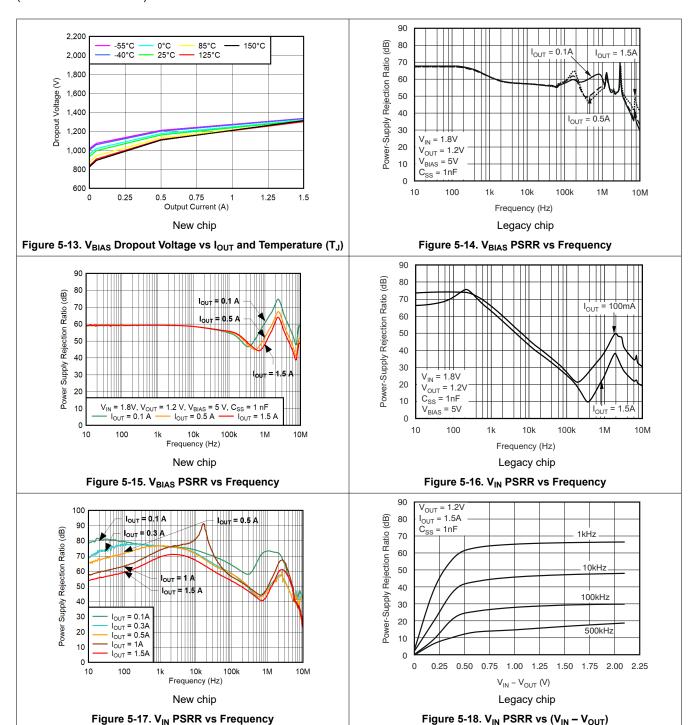
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at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)





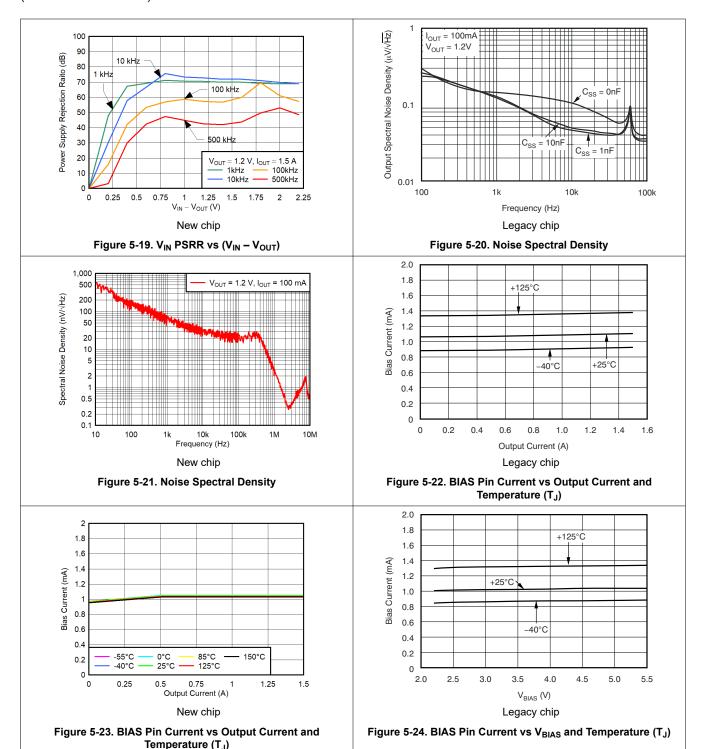
at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



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at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



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at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)

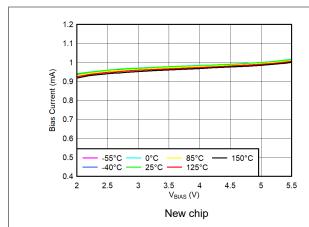


Figure 5-25. BIAS Pin Current vs V<sub>BIAS</sub> and Temperature (T<sub>J</sub>)

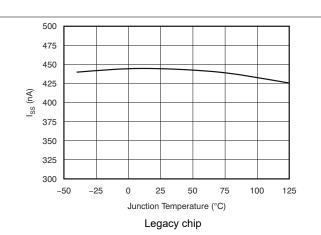


Figure 5-26. Soft-Start Charging Current ( $I_{SS}$ ) vs Temperature ( $I_{J}$ )

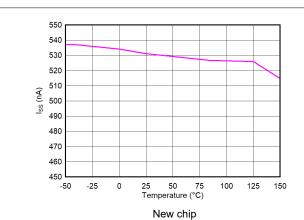


Figure 5-27. Soft-Start Charging Current (I<sub>SS</sub>) vs Temperature

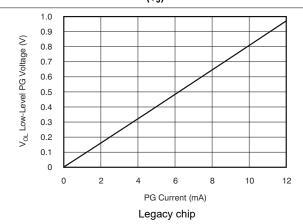
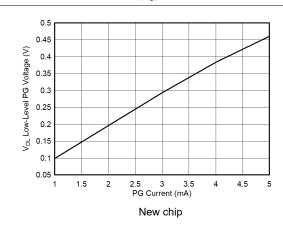


Figure 5-28. Low-Level PG Voltage vs Current





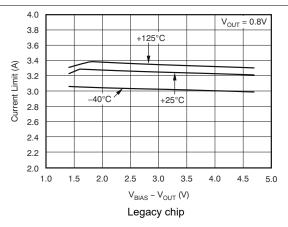
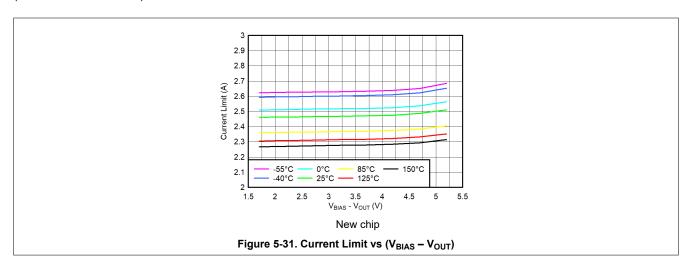


Figure 5-30. Current Limit vs (V<sub>BIAS</sub> – V<sub>OUT</sub>)

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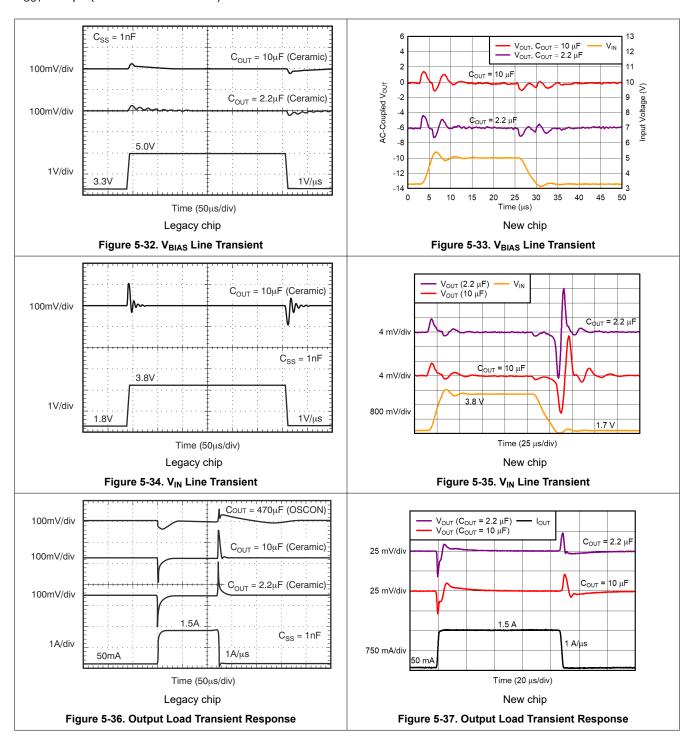
at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 50 mA,  $V_{EN}$  =  $V_{IN}$ ,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



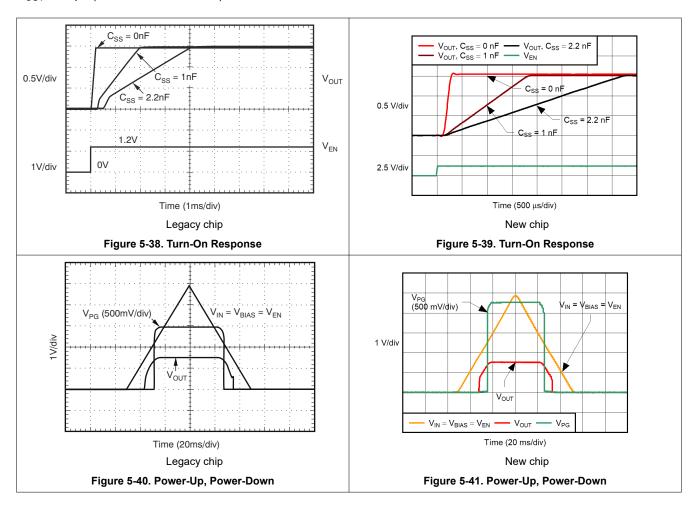


## 5.7 Typical Characteristics: $I_{OUT} = 1 A$

at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 1 A,  $V_{EN}$  =  $V_{IN}$  = 1.8 V,  $V_{OUT}$  = 1.5 V,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



at  $T_J$  = 25°C,  $V_{IN}$  =  $V_{OUT(nom)}$  + 0.3 V,  $V_{BIAS}$  = 5 V,  $I_{OUT}$  = 1 A,  $V_{EN}$  =  $V_{IN}$  = 1.8 V,  $V_{OUT}$  = 1.5 V,  $C_{IN}$  = 1  $\mu$ F,  $C_{BIAS}$  = 4.7  $\mu$ F, and  $C_{OUT}$  = 10  $\mu$ F (unless otherwise noted)



### **6 Detailed Description**

#### 6.1 Overview

The TPS748 is a low-dropout regulator that features soft-start capability. This regulator uses a low current bias input to power all internal control circuitry, allowing the NMOS-pass transistor to regulate very low input and output voltages. Using an NMOS-pass transistor offers several critical advantages for many applications. Unlike a PMOS topology device, the output capacitor has little effect on loop stability. This architecture allows the TPS74801-Q1 to be stable with any capacitor type of value 2.2 μF or greater. Transient response is also superior to PMOS topologies, particularly for low V<sub>IN</sub> applications. The TPS74801-Q1 features a programmable voltage-controlled soft-start circuit that provides a smooth, monotonic start-up and limits start-up inrush currents that can be caused by large capacitive loads. A power-good (PG) output is available to allow supply monitoring and sequencing of other supplies. An enable (EN) pin with hysteresis and deglitch allows slow-ramping signals to be used for sequencing the device. The low V<sub>IN</sub> and V<sub>OUT</sub> capability allows for inexpensive, easy-to-design, and efficient linear regulation between the multiple supply voltages often required by processor-intensive systems.

### 6.2 Functional Block Diagrams

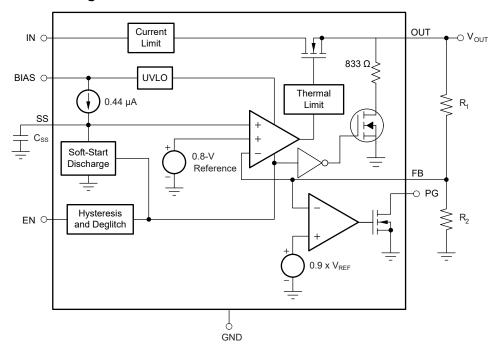


Figure 6-1. Legacy Chip Functional Block Diagram

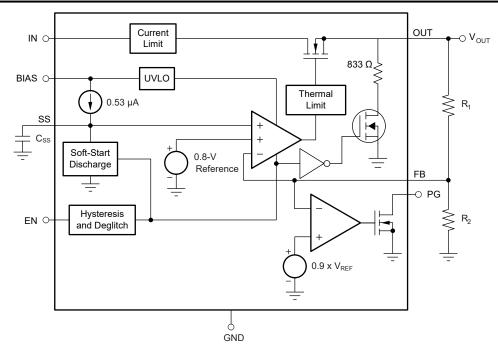


Figure 6-2. New Chip Functional Block Diagram

#### **6.3 Feature Description**

### 6.3.1 Programmable Soft-Start

The TPS74801-Q1 features a programmable, monotonic, voltage-controlled soft-start that is set with an external capacitor ( $C_{SS}$ ). This feature is important for many applications because soft-start eliminates power-up initialization problems when powering FPGAs, DSPs, or other processors. The controlled voltage ramp of the output also reduces peak inrush current during start-up, minimizing start-up transient events to the input power bus.

To achieve a linear and monotonic soft-start, the TPS74801-Q1 error amplifier tracks the voltage ramp of the external soft-start capacitor until the voltage exceeds the internal reference. The soft-start ramp time depends on the soft-start charging current ( $I_{SS}$ ), soft-start capacitance ( $C_{SS}$ ), and the internal reference voltage ( $V_{REF}$ ), and can be calculated using Equation 1:

$$t_{SS} = \frac{(V_{REF} \times C_{SS})}{I_{SS}}$$
 (1)

If large output capacitors are used, the device current limit ( $I_{CL}$ ) and the output capacitor can set the start-up time. In this case, the start-up time is given by Equation 2:

$$t_{SSCL} = \frac{(V_{OUT(NOM)} \times C_{OUT})}{I_{CL(MIN)}}$$
(2)

where:

- V<sub>OUT(NOM)</sub> is the nominal output voltage
- C<sub>OUT</sub> is the output capacitance
- · I<sub>CL(MIN)</sub> is the minimum current limit for the device

In applications where monotonic start-up is required, the soft-start time given by Equation 1 must be set greater than Equation 2.

The maximum recommended soft-start capacitor is  $0.015~\mu F$ . Larger soft-start capacitors can be used and do not damage the device; however, the soft-start capacitor discharge circuit can possibly be unable to fully discharge the soft-start capacitor when enabled. Soft-start capacitors larger than  $0.015~\mu F$  can be a problem in applications where the enable pin must be rapidly pulsed while still requiring the device to soft-start from ground.  $C_{SS}$  must be low-leakage; X7R, X5R, or C0G dielectric materials are preferred. See Table 7-3 for suggested soft-start capacitor values.

#### 6.3.2 Sequencing Requirements

 $V_{IN}$ ,  $V_{BIAS}$ , and  $V_{EN}$  can be sequenced in any order without causing damage to the device. However, for the soft-start function to work as intended, certain sequencing rules must be applied. Connecting EN to IN is acceptable for most applications, as long as  $V_{IN}$  is greater than 1.1 V and the ramp rate of  $V_{IN}$  and  $V_{BIAS}$  is faster than the set soft-start ramp rate. If the ramp rate of the input sources is slower than the set soft-start time, the output tracks the slower supply minus the dropout voltage until the set output voltage is reached. If EN is connected to BIAS, the device soft-starts as programmed, provided that  $V_{IN}$  is present before  $V_{BIAS}$ . If  $V_{BIAS}$  and  $V_{EN}$  are present before  $V_{IN}$  is applied and the set soft-start time has expired, then  $V_{OUT}$  tracks  $V_{IN}$ . If the soft-start time has not expired, the output tracks  $V_{IN}$  until  $V_{OUT}$  reaches the value set by the charging soft-start capacitor. Figure 6-3 shows the use of an RC-delay circuit to hold off  $V_{EN}$  until  $V_{BIAS}$  has ramped. This technique can also be used to drive EN from  $V_{IN}$ . An external control signal can also be used to enable the device after  $V_{IN}$  and  $V_{BIAS}$  are present.

#### Note

When  $V_{BIAS}$  and  $V_{EN}$  are present and  $V_{IN}$  is not supplied, this device outputs approximately 50  $\mu A$  of current from OUT. Although this condition does not cause any damage to the device, the output current can charge up the OUT node if total resistance between OUT and GND (including external feedback resistors) is greater than 10 k $\Omega$ .

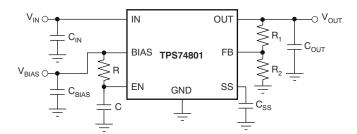


Figure 6-3. Soft-Start Delay Using an RC Circuit to Enable the Device

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#### 6.3.3 Output Noise

The TPS74801-Q1 provides low output noise when a soft-start capacitor is used. When the device reaches the end of the soft-start cycle, the soft-start capacitor serves as a filter for the internal reference. By using a 0.001- $\mu$ F soft-start capacitor, the output noise is reduced by half and is typically 30- $\mu$ V<sub>RMS</sub> for a 1.2-V output (10 Hz to 100 kHz). Further increasing C<sub>SS</sub> has little effect on noise. Because most of the output noise is generated by the internal reference, the noise is a function of the set output voltage. The following equations calculate the RMS noise with a 0.001- $\mu$ F soft-start capacitor for the legacy and new chip, respectively:

$$V_N = 25 \left(\frac{\mu V_{RMS}}{V}\right) \times V_{OUT}\left(V\right)$$
 (Legacy Chip) (3)

$$V_N = 20 \left(\frac{\mu V_{RMS}}{V}\right) \times V_{OUT} \left(V\right) \text{(New Chip)} \tag{4}$$

The low output noise of the TPS74801-Q1 makes the device a good choice for powering transceivers, PLLs, or other noise-sensitive circuitry.

#### 6.3.4 Enable and Shutdown

The enable (EN) pin is active high and is compatible with standard digital signaling levels.  $V_{EN}$  below 0.4 V turns the regulator off, while  $V_{EN}$  above 1.1 V turns the regulator on. Unlike many regulators, the enable circuitry has hysteresis and deglitching for use with relatively slowly ramping analog signals. This configuration allows the TPS74801-Q1 to be enabled by connecting the output of another supply to the EN pin. The enable circuitry typically has 50 mV of hysteresis and a deglitch circuit to help avoid on-off cycling as a result of small glitches in the  $V_{EN}$  signal.

The enable threshold is typically 0.8 V and varies with temperature and process variations. Temperature variation is approximately –1 mV/°C; process variation accounts for most of the rest of the variation to the 0.4-V and 1.1-V limits. If precise turn-on timing is required, a fast rise-time signal must be used to enable the TPS74801-Q1.

If not used, EN can be connected to either IN or BIAS. If EN is connected to IN, connect the EN pin as close as possible to the largest capacitance on the input to prevent voltage droops on that line from triggering the enable circuit.

#### 6.3.5 Power Good

The power-good (PG) pin is an open-drain output and can be connected to any 5.5-V or lower rail through an external pullup resistor. This pin requires at least 1.1 V on  $V_{BIAS}$  in order to have a valid output. The PG output is high-impedance when  $V_{OUT}$  is greater than  $V_{IT} + V_{HYS}$ . If  $V_{OUT}$  drops below  $V_{IT}$  or if  $V_{BIAS}$  drops below 1.9 V, the open-drain output turns on and pulls the PG output low. The PG pin also asserts when the device is disabled. The recommended operating condition of the PG pin sink current is up to 1 mA, so the pullup resistor for PG must be in the range of 10 k $\Omega$  to 1 M $\Omega$ . If output voltage monitoring is not needed, the PG pin can be left floating.

#### 6.3.6 Internal Current Limit

The TPS74801-Q1 features a factory-trimmed, accurate current limit that is flat over temperature and supply voltage. The current limit allows the device to supply surges of up to 2 A and maintain regulation. The current limit responds in approximately 10 µs to reduce the current during a short-circuit fault.

The internal current limit protection circuitry of the TPS74801-Q1 is designed to protect against overload conditions. This circuitry is not intended to allow operation above the rated current of the device. Continuously running the TPS74801-Q1 above the rated current degrades device reliability.

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#### 6.3.7 Thermal Protection

Thermal protection disables the output when the junction temperature rises to approximately 160°C, allowing the device to cool. When the junction temperature cools to approximately 140°C, the output circuitry is enabled. Depending on power dissipation, thermal resistance, and ambient temperature the thermal protection circuit can cycle on and off. This cycling limits the dissipation of the regulator, protecting the regulator from damage as a result of overheating.

Activation of the thermal protection circuit indicates excessive power dissipation or inadequate heat sinking. For reliable operation, junction temperature must be limited to 150°C maximum. To estimate the margin of safety in a complete design (including heat sink), increase the ambient temperature until thermal protection is triggered; use worst-case loads and signal conditions. For good reliability, thermal protection must trigger at least 40°C above the maximum expected ambient condition of the application. This condition produces a worst-case junction temperature of 150°C at the highest expected ambient temperature and worst-case load.

The internal protection circuitry of the TPS74801-Q1 is designed to protect against overload conditions. This circuitry is not intended to replace proper heat sinking. Continuously running the TPS74801-Q1 into thermal shutdown degrades device reliability.

Product Folder Links: TPS74801-Q1

#### 6.4 Device Functional Modes

Table 6-1 shows the conditions that lead to the different modes of operation. See the *Electrical Characteristics* table for parameter values.

Table 6-1.	<b>Device Functional Mode Comparison</b>
	DADAMETED

OPERATING MODE	PARAMETER					
OPERATING WIDDE	V <sub>IN</sub>	V <sub>BIAS</sub>	V <sub>EN</sub>	I <sub>OUT</sub>	T <sub>J</sub>	
Normal mode	$V_{IN} \ge V_{OUT (nom)} + V_{DO(IN)}$ and $V_{IN} \ge V_{IN(min)}$	$V_{BIAS} \ge V_{OUT} + V_{DO(BIAS)}$	$V_{EN} \ge V_{HI(EN)}$	I <sub>OUT</sub> < I <sub>CL</sub>	T <sub>J</sub> < T <sub>SD</sub> for shutdown	
Dropout mode	$V_{IN(min)} < V_{IN} < V_{OUT (nom)} + V_{DO(IN)}$	$V_{BIAS} < V_{OUT} + V_{DO(BIAS)}$	$V_{EN} > V_{HI(EN)}$	I <sub>OUT</sub> < I <sub>CL</sub>	T <sub>J</sub> < T <sub>SD</sub> for shutdown	
Disabled mode (any true condition disables the device)	V <sub>IN</sub> < V <sub>UVLO(IN)</sub>	V <sub>BIAS</sub> < V <sub>BIAS(UVLO)</sub>	V <sub>EN</sub> < V <sub>LO(EN)</sub>	_	$T_J \ge T_{SD}$ for shutdown	

### 6.4.1 Normal Operation

The device regulates to the nominal output voltage when the following conditions are met:

- The input voltage is greater than the nominal output voltage plus the dropout voltage (V<sub>OUT(nom)</sub> + V<sub>DO(IN)</sub>)
- The bias voltage is greater than the nominal output voltage plus the dropout voltage (V<sub>OUT(nom)</sub> + V<sub>DO(BIAS)</sub>)
- The output current is less than the current limit (I<sub>OUT</sub> < I<sub>CI</sub>)
- The device junction temperature is less than the thermal shutdown temperature ( $T_J < T_{SD(shutdown)}$ )
- The enable voltage has previously exceeded the enable rising threshold voltage and has not yet decreased to less than the enable falling threshold

### 6.4.2 Dropout Operation

If the input voltage is lower than the nominal output voltage plus the specified dropout voltage, but all other conditions are met for normal operation, the device operates in dropout mode. Similarly, if the bias voltage is lower than the nominal output voltage plus the specified dropout voltage, but all other conditions are met for normal operation, the device operates in dropout mode as well. In this mode, the output voltage tracks the input voltage. During this mode, the transient performance of the device becomes significantly degraded because the pass transistor is in the ohmic or triode region, and functions as a switch. Line or load transients in dropout can result in large output voltage deviations.

When the device is in a steady dropout state, defined as when the device is in dropout ( $V_{IN} < V_{OUT} + V_{DO(IN)}$  or  $V_{BIAS} < V_{OUT} + V_{DO(BIAS)}$  directly after being in normal regulation state, but not during start up), the pass transistor is driven into the ohmic or triode region. When the input voltage returns to a value greater than or equal to the nominal output voltage plus the dropout voltage ( $V_{OUT(NOM)} + V_{DO(IN)}$ ), the output voltage can overshoot for a short time when the device pulls the pass transistor back into the linear region.

### 6.4.3 Disabled

The output of the device can be shutdown by forcing the voltage of the enable pin to less than  $V_{IL(EN)}$  (see the *Electrical Characteristics* table). When disabled, the pass transistor is turned off, internal circuits are shutdown, and the output voltage is actively discharged to ground by an internal discharge circuit from the output to ground.

The device is disabled under the following conditions:

- The input or bias voltages are below the respective minimum specifications
- The enable voltage is less than the enable falling threshold voltage or has not yet exceeded the enable rising threshold
- The device junction temperature is greater than the thermal shutdown temperature

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# 7 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 7.1 Application Information

The TPS74801-Q1 belongs to a family of low dropout regulators that feature soft-start capability. This regulator uses a low current bias input to power all internal control circuitry, allowing the NMOS pass transistor to regulate very low input and output voltages.

Using an NMOS pass transistor offers several critical advantages for many applications. Unlike a PMOS topology device, the output capacitor has little effect on loop stability. This architecture allows the TPS74801-Q1 to be stable with any capacitor type of value 2.2  $\mu F$  or greater. Transient response is also superior to PMOS topologies, particularly for low  $V_{IN}$  applications.

The TPS74801-Q1 features a programmable voltage-controlled soft-start circuit that provides a smooth, monotonic start-up and limits start-up inrush currents that can be caused by large capacitive loads. A power-good (PG) output is available to allow supply monitoring and sequencing of other supplies. An enable (EN) pin with hysteresis and deglitch allows slow-ramping signals to be used for sequencing the device. The low  $V_{IN}$  and  $V_{OUT}$  capability allows for inexpensive, easy-to-design, and efficient linear regulation between the multiple supply voltages often present in processor-intensive systems.

### 7.2 Typical Application

Figure 7-1 shows the typical application circuit for the TPS74801-Q1 adjustable output device.

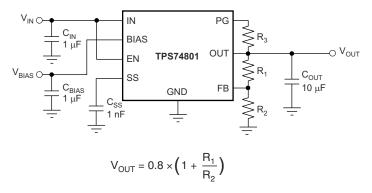


Figure 7-1. Typical Application Circuit for the TPS74801-Q1 (Adjustable)

#### 7.2.1 Design Requirements

For this design example, use the parameters listed in Table 7-1 as the input parameters.

**Table 7-1. Design Parameters** 

PARAMETER	DESIGN REQUIREMENT
Input voltage	2.1 V, ±3%
Bias voltage	5.0 V
Output voltage	1.8 V, ±1%
Output current	1.5 A (maximum), 10 mA (minimum)
Start-up time	< 25 ms

Product Folder Links: TPS74801-Q1

### 7.2.2 Detailed Design Procedure

 $R_1$  and  $R_2$  can be calculated for any output voltage using the formula shown in Figure 7-1. See Table 7-2 for sample resistor values of common output voltages. To achieve the maximum accuracy specifications,  $R_2$  must be  $\leq 4.99 \text{ k}\Omega$ .

Table 7-2. Standard 1% Resistor Values for Programming the Output Voltage (1)

R <sub>1</sub> (kΩ)	R <sub>2</sub> (kΩ)	V <sub>OUT</sub> (V)
Short	Open	0.8
0.619	4.99	0.9
1.13	4.53	1
1.37	4.42	1.05
1.87	4.99	1.1
2.49	4.99	1.2
4.12	4.75	1.5
3.57	2.87	1.8
3.57	1.69	2.5
3.57	1.15	3.3

(1)  $V_{OUT} = 0.8 \times (1 + R_1 / R_2)$ .

Table 7-3. Standard Capacitor Values for Programming the Soft-Start Time (1)

C <sub>SS</sub>	SOFT-START TIME (Legacy Chip)	SOFT-START TIME (New Chip)
Open	0.1 ms	0.25 ms
270 pF	0.5 ms	0.4 ms
560 pF	1 ms	0.8 ms
2.7 nF	5 ms	4.1 ms
5.6 nF	10 ms	8.5 ms
0.01 μF	18 ms	15 ms

<sup>(1)</sup>  $t_{SS}(s) = 0.8 \times C_{SS}(F) / I_{SS}$ .

#### 7.2.2.1 Input, Output, and Bias Capacitor Requirements

The device is designed to be stable for all available types and values of output capacitors  $\geq$  2.2  $\mu$ F. The device is also stable with multiple capacitors in parallel, which can be of any type or value.

The capacitance required on the IN and BIAS pins strongly depends on the input supply source impedance. To counteract any inductance in the input, the minimum recommended capacitor for  $V_{IN}$  and  $V_{BIAS}$  is 1  $\mu$ F. If  $V_{IN}$  and  $V_{BIAS}$  are connected to the same supply, the recommended minimum capacitor for  $V_{BIAS}$  is 4.7  $\mu$ F. Use good-quality, low-ESR capacitors on the input; ceramic X5R and X7R capacitors are preferred. Place these capacitors as close to the pins as possible for optimum performance.

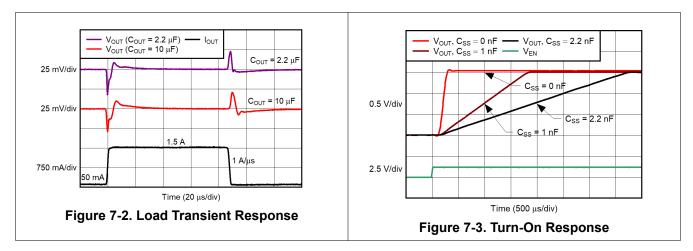
#### 7.2.2.2 Transient Response

The TPS74801-Q1 is designed to have excellent transient response for most applications with a small amount of output capacitance. In some cases, the transient response can be limited by the transient response of the input supply. This limitation is especially true in applications where the difference between the input and output is less than 300 mV. In this case, adding additional input capacitance improves the transient response much more than just adding additional output capacitance does. With a solid input supply, adding additional output capacitance reduces undershoot and overshoot during a transient event; see the *Output Load Transient Response* curves in the *Typical Characteristics* section. Because the TPS74801-Q1 is stable with output capacitors as low as 2.2  $\mu$ F, many applications can then need very little capacitance at the LDO output. For these applications, local bypass capacitance for the powered device can be sufficient to meet the transient requirements of the application. This design reduces the total solution cost by avoiding the need to use expensive, high-value capacitors at the LDO output.

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### 7.2.3 Application Curves



### 7.3 Power Supply Recommendations

The TPS74801-Q1 is designed to operate from an input voltage up to 5.5 V, provided the bias rail is at least 1.3 V higher than the input supply and dropout requirements are met. The bias rail and the input supply must both provide adequate headroom and current for the device to operate normally. Connect a low output impedance power supply directly to the IN pin. This supply must have at least 1  $\mu$ F of capacitance near the IN pin for optimal performance. A supply with similar requirements must also be connected directly to the BIAS rail with a separate 0.1  $\mu$ F or larger capacitor. If the IN pin is tied to the BIAS pin, a minimum 4.7- $\mu$ F capacitor is required for performance. To increase the overall PSRR of the solution at higher frequencies, use a pi-filter or ferrite bead before the input capacitor.

#### 7.4 Layout

### 7.4.1 Layout Guidelines

#### 7.4.1.1 Layout Recommendations and Power Dissipation

An optimal layout can greatly improve transient performance, PSRR, and noise. To minimize the voltage drop on the input of the device during load transients, the capacitance on IN and BIAS must be connected as close as possible to the device. This capacitance also minimizes the effects of parasitic inductance and resistance of the input source and can, therefore, improve stability. To achieve optimal transient performance and accuracy, the top side of R<sub>1</sub> in Figure 7-1 must be connected as close as possible to the load. If BIAS is connected to IN, connect BIAS as close to the sense point of the input supply as possible. This connection minimizes the voltage drop on BIAS during transient conditions and can improve the turn-on response.

Knowing the device power dissipation and proper sizing of the thermal plane that is connected to the thermal pad is critical to avoiding thermal shutdown and to provide reliable operation. Power dissipation of the device depends on input voltage and load conditions and can be calculated using Equation 5:

$$P_{D} = (V_{IN} - V_{OUT}) \times I_{OUT}$$
 (5)

Power dissipation can be minimized and greater efficiency can be achieved by using the lowest possible input voltage necessary to achieve the required output voltage regulation.

The primary conduction path for heat is through the exposed pad to the printed circuit board (PCB). The pad can be connected to ground or be left floating; however, the pad must be attached to an appropriate amount of copper PCB area to make sure the device does not overheat. The maximum junction-to-ambient thermal resistance depends on the maximum ambient temperature, maximum device junction temperature, and power dissipation of the device and can be calculated using Equation 6:

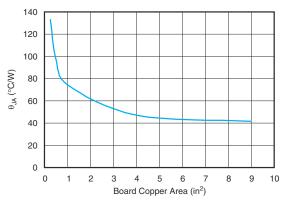
$$R_{\theta JA} = \frac{(150^{\circ}C - T_{A})}{P_{D}}$$
 (6)

Knowing the maximum  $R_{\theta JA}$ , the minimum amount of PCB copper area needed for appropriate heat sinking can be estimated using Figure 7-4.

Figure 7-4 shows the variation of  $R_{\theta JA}$  as a function of ground plane copper area in the board. This figure is intended only as a guideline to demonstrate the effects of heat spreading in the ground plane and is not intended to be used to estimate actual thermal performance in real application environments.

#### **Note**

When the device is mounted on an application PCB, use  $\Psi_{JT}$  and  $\Psi_{JB}$ , as explained in the *Estimating Junction Temperature* section.



R<sub>0,JA</sub> value at board size of 9 in<sup>2</sup> (that is, 3-in × 3-in) is a JEDEC standard.

Figure 7-4. R<sub>θJA</sub> vs Board Size

#### 7.4.1.2 Estimating Junction Temperature

Using the thermal metrics  $\Psi_{JT}$  and  $\Psi_{JB}$ , as shown in the *Thermal Information* table, the junction temperature can be estimated with corresponding formulas (given in Equation 7). For backwards compatibility, an older  $R_{\theta JC}$ , *Top* parameter is listed as well.

$$\Psi_{JT}: \quad T_{J} = T_{T} + \Psi_{JT} \cdot P_{D}$$

$$\Psi_{JB}: \quad T_{J} = T_{B} + \Psi_{JB} \cdot P_{D}$$
(7)

Where  $P_D$  is the power dissipation shown by Equation 7,  $T_T$  is the temperature at the center-top of the device package, and  $T_B$  is the PCB temperature measured 1mm away from the device package *on the PCB surface* (see Figure 7-6).

#### Note

Both  $T_T$  and  $T_B$  can be measured on actual application boards using a thermo-gun (an infrared thermometer).

For more information about measuring  $T_T$  and  $T_B$ , see the *Using New Thermal Metrics* application note, available for download at www.ti.com.

In reference to Figure 7-5, the new thermal metrics ( $\Psi_{JT}$  and  $\Psi_{JB}$ ) have very little dependency on board size. That is, using  $\Psi_{JT}$  or  $\Psi_{JB}$  with Equation 7 is a good way to estimate  $T_J$  by simply measuring  $T_T$  or  $T_B$ , regardless of the application board size.

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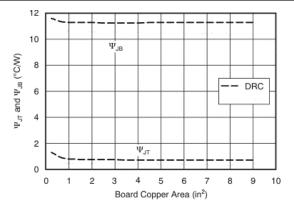
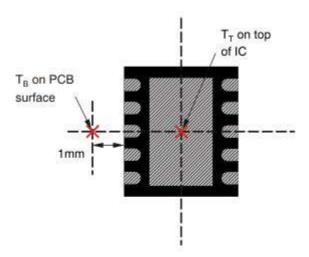


Figure 7-5.  $\Psi_{JT}$  and  $\Psi_{JB}$  vs Board Size

For a more detailed discussion of why TI does not recommend using  $R_{\theta JC(top)}$  to determine thermal characteristics, see the *Using New Thermal Metrics* application note, available for download at www.ti.com. For further information, see the *Semiconductor and IC Package Thermal Metrics* application note, also available on the TI website.



### (a) Example DRC (SON) Package Measurement

- A.  $T_T$  is measured at the center of both the X- and Y-dimensional axes.
- B.  $T_B$  is measured below the package lead on the PCB surface.

Figure 7-6. Measuring Points for  $T_{T}$  and  $T_{B}$ 



## 7.4.2 Layout Example

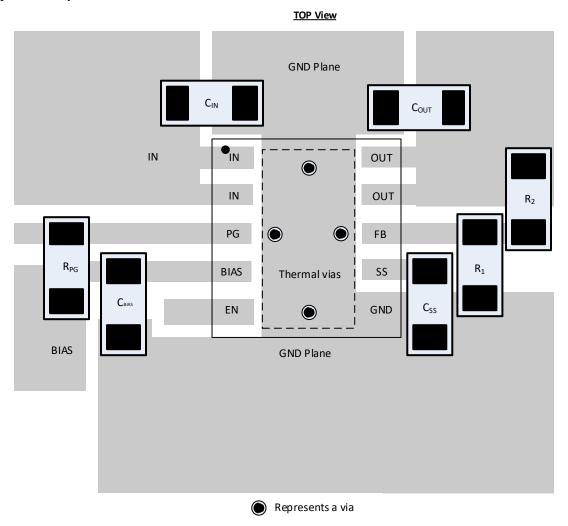


Figure 7-7. Layout Example: DRC Package

## 8 Device and Documentation Support

### **8.1 Documentation Support**

#### 8.1.1 Related Documentation

For related documentation see the following:

Texas Instruments, Using New Thermal Metrics application note

#### 8.1.2 Device Nomenclature

**Table 8-1. Device Nomenclature** 

PRODUCT <sup>(1)</sup>	V <sub>OUT</sub>
TPS74801 <b>Q(W)yyyzM3Q1</b>	Q indicates that this device is a grade-1 device in accordance with the AEC-Q100 standard.  W indicates that the package has wettable flanks (new chip only).  yyy is the package designator.  z is the package quantity.  M3 is a suffix designator for devices that only use the latest manufacturing flow (CSO: RFB). Devices without this suffix can ship with the legacy chip (CSO: DLN) or the new chip (CSO: RFB). The reel packaging label provides CSO information to distinguish which chip is being used. Device performance for new and legacy chips is denoted throughout the document.  Q1 indicates that this device is an automotive grade (AEC-Q100) device.

<sup>(1)</sup> For the most current package and ordering information see the Package Option Addendum at the end of this document, or visit the device product folder on www.ti.com.

### 8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 8.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the guick design help you need.

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### 8.4 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

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### **9 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision D (December 2023) to Revision E (September 2024)	Page
•	Added $V_{IN}$ Dropout Voltage vs ( $V_{BIAS} - V_{OUT}$ ) and Temperature ( $T_A$ ) curve to Typical Characteristics: $I_{OU}$ 50 mA section	
•	Added active pulldown to Legacy Chip Functional Block Diagram and added New Chip Functional Block Diagram	(
С	changes from Revision C (July 2023) to Revision D (December 2023)	Page
	Added device verbiage throughout document to differentiate legacy chip and new chip information  Changed <i>Description</i> section: Changed <i>Turn-On Response</i> figure and added temperature range for new chip	
•	Changed <i>Typical Characteristics</i> sections to show legacy chip and new chip data side by side and delete <i>Dropout Voltage vs V<sub>BIAS</sub>-V<sub>OUT</sub></i> curves	
•	Changed images in Estimating Junction Temperature section	Page16  Page1 1 1 25
•	Deleted RGW Example figure from Layout Example section	
•	Added Device Nomenclature section	28

# 10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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8-Nov-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
TPS74801QDRCRM3Q1	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 150	QVK
TPS74801QDRCRM3Q1.A	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 150	QVK
TPS74801QRGWRM3Q1	Active	Production	VQFN (RGW)   20	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TPS 74801Q
TPS74801QRGWRM3Q1.A	Active	Production	VQFN (RGW)   20	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TPS 74801Q
TPS74801QRGWRQ1	Active	Production	VQFN (RGW)   20	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TPS 74801Q
TPS74801QRGWRQ1.A	Active	Production	VQFN (RGW)   20	3000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TPS 74801Q
TPS74801QWDRCRQ1	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 105	SMF
TPS74801QWDRCRQ1.A	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 105	SMF
TPS74801TDRCRQ1	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 105	QVK
TPS74801TDRCRQ1.A	Active	Production	VSON (DRC)   10	3000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 105	QVK

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



# **PACKAGE OPTION ADDENDUM**

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Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF TPS74801-Q1:

Catalog: TPS74801

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS74801QDRCRM3Q1	VSON	DRC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
TPS74801QRGWRM3Q1	VQFN	RGW	20	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2
TPS74801QRGWRQ1	VQFN	RGW	20	3000	330.0	12.4	5.3	5.3	1.1	8.0	12.0	Q2
TPS74801QWDRCRQ1	VSON	DRC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
TPS74801TDRCRQ1	VSON	DRC	10	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2



www.ti.com 8-Aug-2025



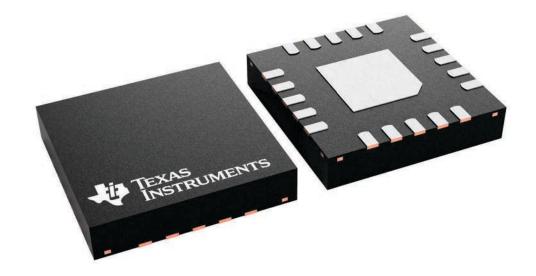
#### \*All dimensions are nominal

7 111 01111011010110 0110 11011111101							
Device	Device Package Type		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS74801QDRCRM3Q1	VSON	DRC	10	3000	367.0	367.0	35.0
TPS74801QRGWRM3Q1	VQFN	RGW	20	3000	367.0	367.0	35.0
TPS74801QRGWRQ1	VQFN	RGW	20	3000	367.0	367.0	35.0
TPS74801QWDRCRQ1	VSON	DRC	10	3000	360.0	360.0	36.0
TPS74801TDRCRQ1	VSON	DRC	10	3000	367.0	367.0	35.0

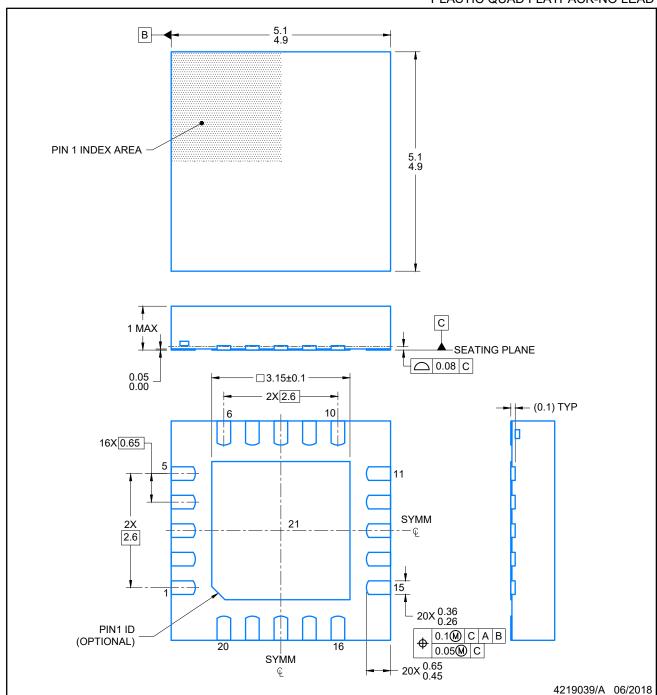
5 x 5, 0.65 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



PLASTIC QUAD FLATPACK-NO LEAD

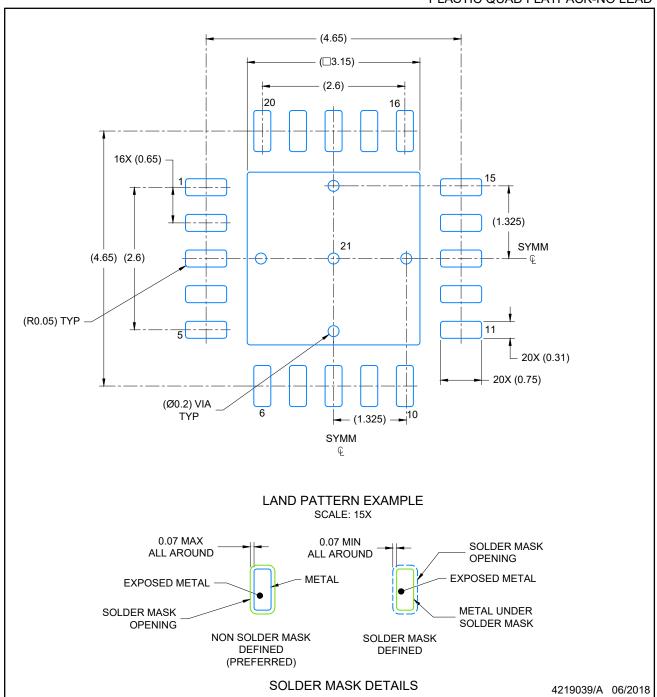


### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLATPACK-NO LEAD

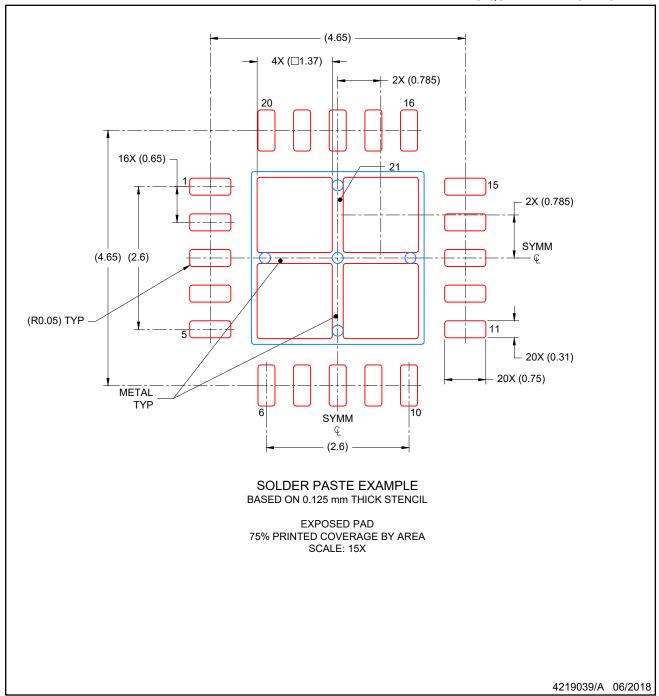


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



3 x 3, 0.5 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.





NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



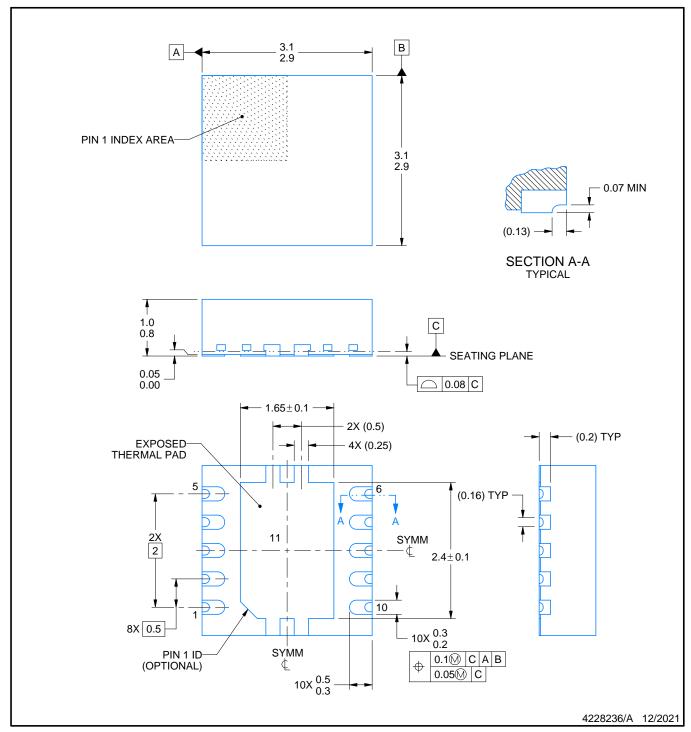


NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



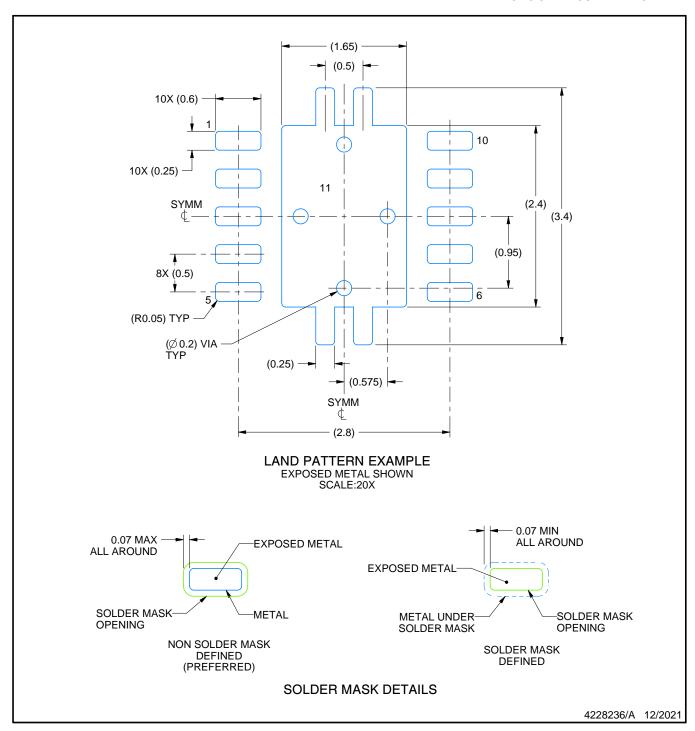




#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.

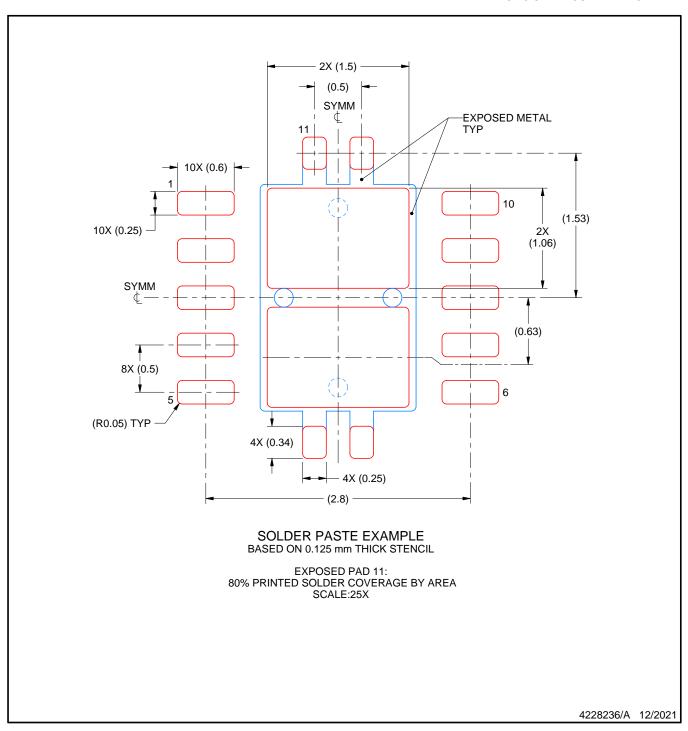




NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.





NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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